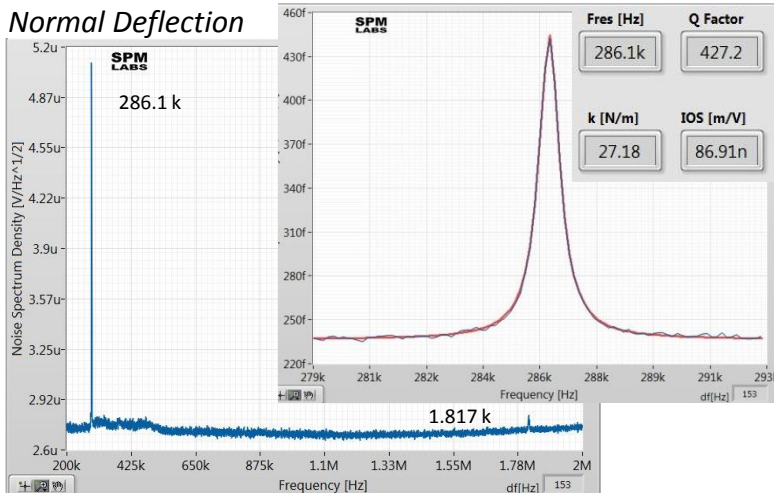
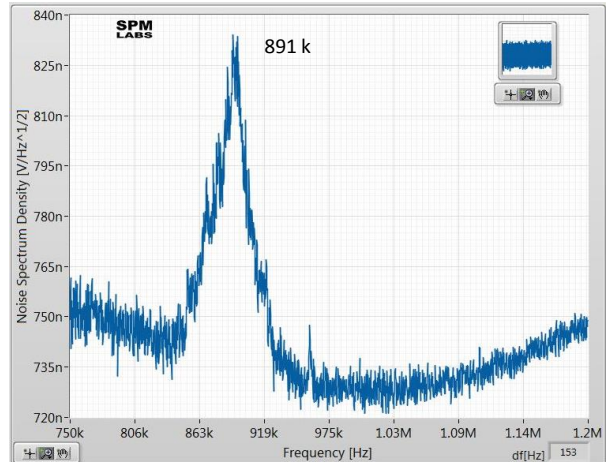


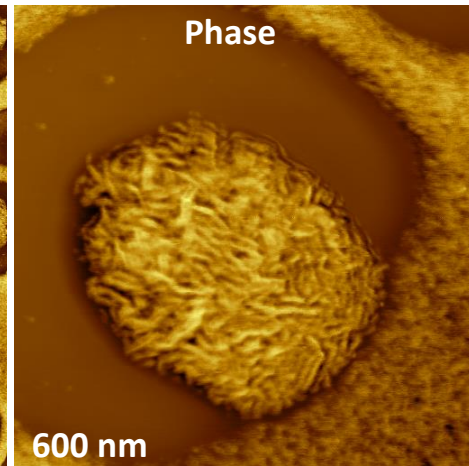
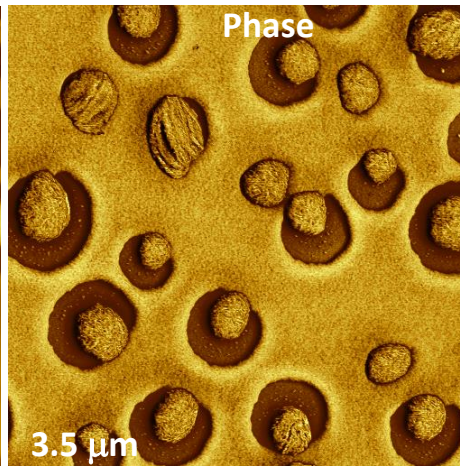
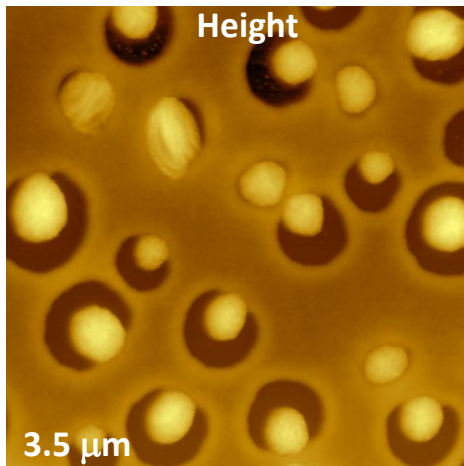
Normal Deflection



Lateral Deflection



Si probe 125/35/4 is most commonly used for AM-PI studies, and it provides high-resolution imaging on a variety of samples. The images of a recrystallized sample of polystyrene and low-density polyethylene (PS/LDPE) blend and block copolymer of polystyrene and poly(methyl methacrylate) – PS-*b*-PMMA are shown below. Visualization of nanoscale structures such as LDPE lamellae and blocks of microphase separation in PS-*b*-PMMA is routinely achieved with such probes.



Polymer blend: PS/LDPE

Block copolymer:
PS-*b*-PMMA

